

## ■ Safety Recognized of ceramic chip capacitors

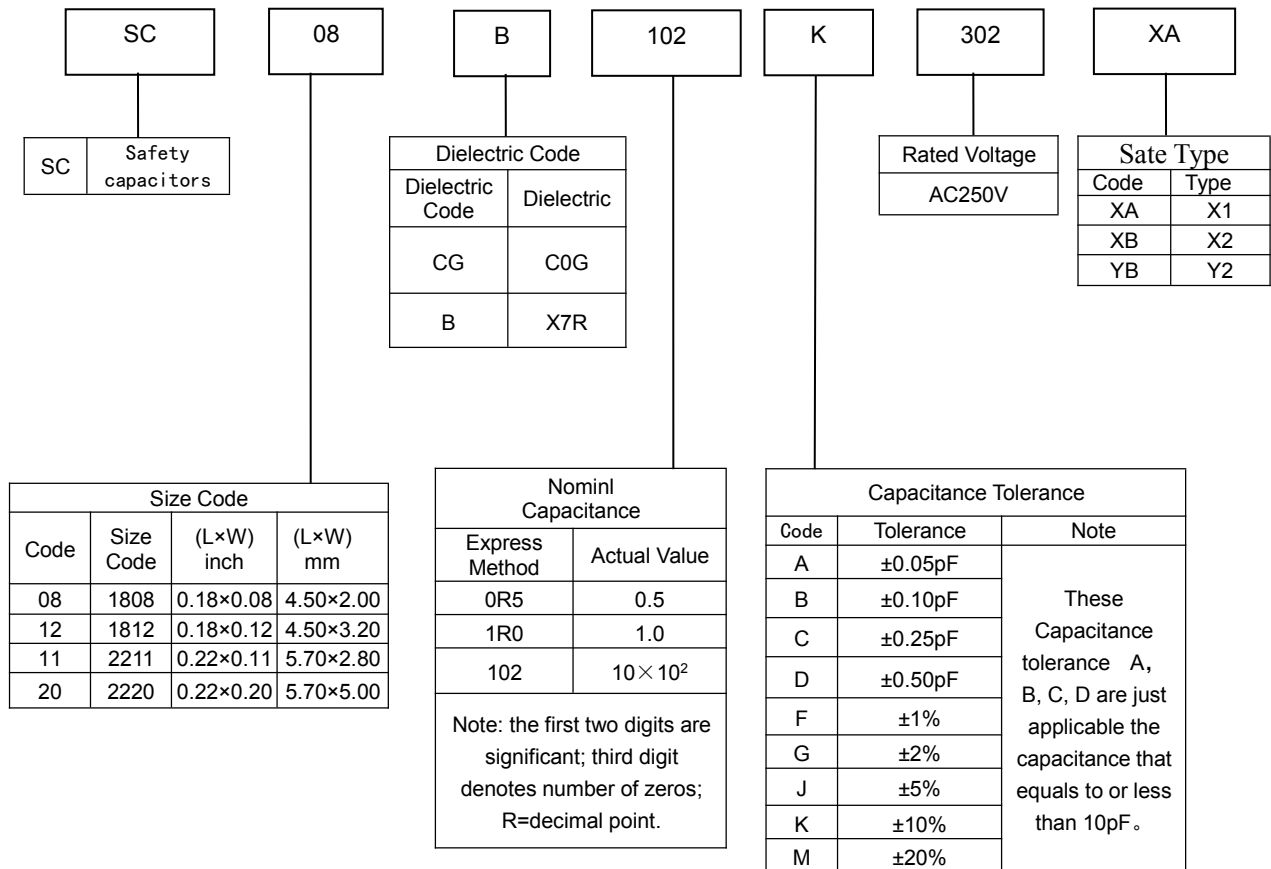
### ◆ Feature

- \* A New monolithic structure capacitor for small,high-capacitance capability of operating at high-voltage levels.
- \* Available for equipment base on 60384-14 standard
- \* Only for reflow soldering
- \* Fit for use on thin type equipment.



### ◆ Application

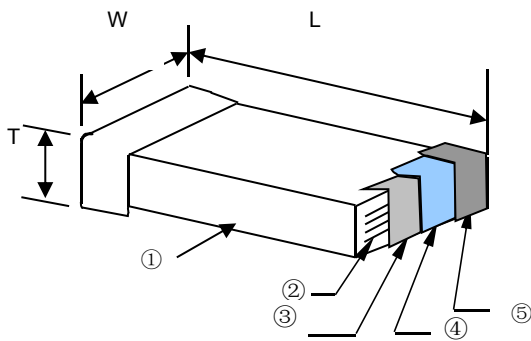
- \* Ideal for use on line filters and couplings for DAA modems without transformers.
- \* Ideal for use on line filters for information equipment.

**◆ How To Order**


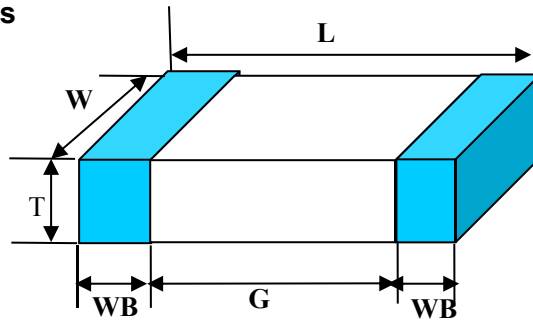
**◆ Product application voltage**

Code	Peak pulse voltage in use (kV)	Peak pulse voltage applied before durability test (kV)
XA	$2.5kV < U \leq 4.0kV$	$C_R \leq 1.0\mu F, 4$ $C_R > 1.0\mu F, 4/\sqrt{C_R}$
XB	$\leq 2.5kV$	$C_R \leq 1.0\mu F, 2.5$ $C_R > 1.0\mu F, 2.5/\sqrt{C_R}$

Code	Rated Voltage (V)	Peak pulse voltage applied before durability test (kV)
YB	$150V \leq U \leq 250V$	5.0

**◆ Product Structure**


NO	Name
①	Ceramic dielectric
②	Inner electrode
③	Substrate electrode
④	Nickel Layer
⑤	Tin Layer

**◆ Product Dimensions**


Type		Dimensions (mm)				
British expression	Metric expression	L	W	T	WB	G
1808	4520	$4.80 \pm 0.20$	$2.00 \pm 0.20$	$\leq 2.50$	$\leq 0.7$	$\geq 4.0$
1812	4532	$4.80 \pm 0.20$	$3.20 \pm 0.20$	$\leq 3.50$	$\leq 0.7$	$\geq 4.0$
2211	5728	$5.80 \pm 0.40$	$2.80 \pm 0.30$	$\leq 3.50$	$\leq 1.0$	$\geq 4.0$
2220	5750	$5.80 \pm 0.40$	$5.00 \pm 0.40$	$\leq 3.50$	$\leq 1.0$	$\geq 4.0$

Note: We can design according to customer special requirements.

**◆ Temperature Coefficient /Characteristics**

Dielectric	Reference Temperature Point	Temperature Coefficient	Operation Temperature Range
COG	20°C	0±30 ppm/°C	-55°C~125°C
X7R	20°C	±15%	-55°C~125°C

Note: Nominal temperature coefficient and allowed tolerance of class I are decided by the changing of the capacitance between 20°C and 85°C. Nominal temperature coefficient of class II are decided by the temperature of 20°C.

**◆ Capacitance Range**

Dielectric		X7R									
Dimension		SC08			SC12		SC11	SC20			
Series/thickness		XA	XB	YB	XB	YB	YB	XB	YB		
Nominal capacitance	100pF	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3		
	150pF										
	180pF										
	220pF										
	270pF										
	330pF										
	470pF										
	560pF										
	680pF										
	820pF										
	1nF	2.00±0.3	1.60±0.3	1.60±0.3	1.60±0.3	2.00±0.3	1.60±0.3	1.60±0.3	1.60±0.3	2.00±0.3	
	1.2nF			2.00±0.3							
	1.5nF	2.00±0.3	1.60±0.3	2.00±0.3	1.60±0.3	2.00±0.3	1.60±0.3	1.60±0.3	1.60±0.3	2.00±0.3	
	2.2nF										2.50±0.3
	3.3nF										2.80±0.3
	4.7nF						2.00±0.3				
	10nF										
	15nF								1.80±0.30		
18nF											
22nF											
27nF											
33nF											

Note: 1、Corresponding product design thickness , unit:mm ;  
 2、We can design according to customer special requirements

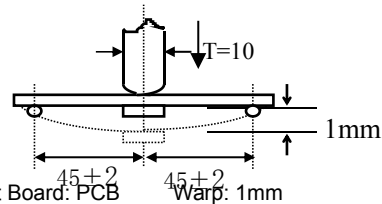
Dielectric		C0G				
Dimension		SC08	SC12	SC11	SC20	
Series/Thickness		YB	YB	YB	YB	
Nominal capacity	5pF	1.60±0.3	1.60±0.3	1.60±0.3	1.60±0.3	
	8.2pF					
	10pF					
	15pF					
	18pF					
	22pF					
	33pF					
	39pF					
	47pF					
	56pF					
	68pF					
	82pF					
	100pF					
	120pF					
		150pF	2.00±0.3	2.00±0.3		
		220pF				
	330pF					
	470pF				2.00±0.3	


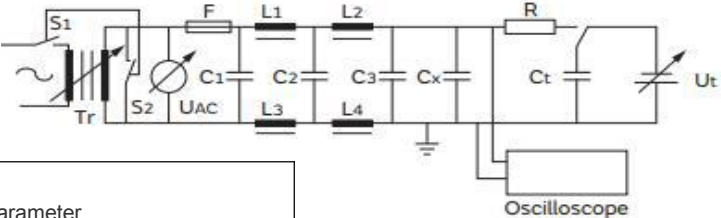
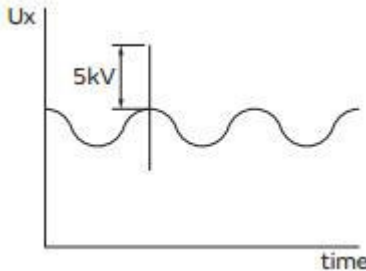
Note: 1、Corresponding product design thickness , unit:mm ; 2、 We can design according to customer special requirements

### ◆ Reliability Test

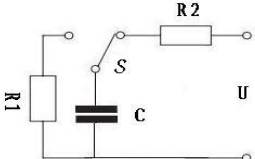
Item	Technical Specification		Test Method and Remarks		
Capacitance	Class I	Should be within the specified tolerance.	Capacitance	Measuring Frequency	Measuring Voltage
			≤1000pF	1MHz±10%	1.0±0.2Vrms
			> 1000 pF	1KHz±10%	
	Class II	Should be within the specified tolerance.	Test Temperature: 25°C±3°C Test Frequency: 1KHz±10% Test Voltage: 1.0±0.2Vrms		
(DF, tanδ) Dissipation Factor	Class I	DF	Capacitance	Measuring Frequency	Measuring Voltage
		≤1/ (400+20C)	C<30 pF	1MHz±10%	1.0±0.2Vrms
		≤0.1%	C≥30pF		
	Class II	X7R	≤25%	Test Frequency: 1KHz ±10% Test Voltage: 1.0± 0.2Vrms	

Item	Technical Specification		Test Method and Remarks												
Insulation Resistance	Class I	C≤10 nF , Ri ≥50000MΩ C> 10 nF , Ri•CR ≥500S	Measuring Voltage: DC500±50V Duration: 60±5s Test Humidity: ≤75% Test Temperature: 25°C±3°C Test Current: ≤50mA												
	Class II	C≤25 nF, Ri≥10000MΩ C>25 nF, Ri•CR>100S													
(DWV) Dielectric Withstanding Voltage	No defects or abnormalities		No failure should be observed when voltage in the table is applied between the terminations for 60 sec. provided the charge/discharge current is less than 50mA. <table border="1" style="margin-left: auto; margin-right: auto;"> <thead> <tr> <th></th> <th>测量电压 Test Voltage</th> </tr> </thead> <tbody> <tr> <td>XA、B</td> <td>DC 1075V</td> </tr> <tr> <td>YB、C</td> <td>AC 1500V</td> </tr> </tbody> </table>		测量电压 Test Voltage	XA、B	DC 1075V	YB、C	AC 1500V						
	测量电压 Test Voltage														
XA、B	DC 1075V														
YB、C	AC 1500V														
Solderability	At least 95% of the terminal electrode is covered by new solder. Visual Appearance: No visible damage.		Preheating conditions: 80 to 120°C; 10~30s.												
			<table border="1" style="width: 100%;"> <tr> <td>Pb-Sn soldering Solder Temperature: 235±5°C Duration: 2±0.5s</td> <td>Lead-free soldering Solder Temperature: 245±5°C Duration: 2±0.5</td> </tr> </table>	Pb-Sn soldering Solder Temperature: 235±5°C Duration: 2±0.5s	Lead-free soldering Solder Temperature: 245±5°C Duration: 2±0.5										
Pb-Sn soldering Solder Temperature: 235±5°C Duration: 2±0.5s	Lead-free soldering Solder Temperature: 245±5°C Duration: 2±0.5														
Resistance to Soldering Heat	<table border="1" style="width: 100%;"> <thead> <tr> <th>Item</th> <th>COG</th> <th>X7R</th> </tr> </thead> <tbody> <tr> <td>ΔC/C</td> <td>≤±2.5% or ±0.25PF, whichever is larger</td> <td>±15%</td> </tr> <tr> <td>DF</td> <td colspan="2">Same to initial value.</td> </tr> <tr> <td>IR</td> <td colspan="2">Same to initial value.</td> </tr> </tbody> </table>		Item	COG	X7R	ΔC/C	≤±2.5% or ±0.25PF, whichever is larger	±15%	DF	Same to initial value.		IR	Same to initial value.		Preheating conditions: 100 to 200°C; 160-120S. Solder Temperature: 265±5°C Duration: 10±1s Clean the capacitor with solvent and examine it with a 10X(min.) microscope. Recovery Time: 24±2h Recovery condition: Room temperature
	Item	COG	X7R												
ΔC/C	≤±2.5% or ±0.25PF, whichever is larger	±15%													
DF	Same to initial value.														
IR	Same to initial value.														
Appearance: No visible damage. At least 95% of the terminal electrode is covered by new solder.															
Impulse voltage	No permanent breakdown or flashover.		Each capacitor shall withstand 24 pulses of the same polarity, the pulse interval time shall not be less than 10S, and the peak value of pulse voltage like the follow table: <table border="1" style="margin-left: auto; margin-right: auto;"> <thead> <tr> <th>Code</th> <th>Peak pulse voltage in use (kV)</th> </tr> </thead> <tbody> <tr> <td>XA</td> <td>4.0</td> </tr> <tr> <td>XB</td> <td>2.5</td> </tr> <tr> <td>YB</td> <td>5</td> </tr> </tbody> </table>	Code	Peak pulse voltage in use (kV)	XA	4.0	XB	2.5	YB	5				
Code	Peak pulse voltage in use (kV)														
XA	4.0														
XB	2.5														
YB	5														

Item	Technical Specification	Test Method and Remarks																					
Resistance to Flexure of Substrate (Bending Strength)	<table border="1" data-bbox="335 336 877 537"> <tr> <td></td> <td>C0G</td> <td>X7R</td> </tr> <tr> <td><math>\Delta C/C</math>:</td> <td><math>\leq \pm 5\%</math> or <math>\pm 0.5pF</math>, whichever is larger.</td> <td><math>\leq \pm 10\%</math></td> </tr> <tr> <td colspan="3">Appearance: No visible damage.</td> </tr> </table>		C0G	X7R	$\Delta C/C$ :	$\leq \pm 5\%$ or $\pm 0.5pF$ , whichever is larger.	$\leq \pm 10\%$	Appearance: No visible damage.			 <p>Test Board: PCB  Speed: 1mm/sec. Unit: mm  The measurement should be made with the board in the bending position.</p>												
	C0G	X7R																					
$\Delta C/C$ :	$\leq \pm 5\%$ or $\pm 0.5pF$ , whichever is larger.	$\leq \pm 10\%$																					
Appearance: No visible damage.																							
Temperature Cycle	<table border="1" data-bbox="335 784 845 896"> <tr> <td>Item</td> <td>C0G</td> <td>X7R</td> </tr> <tr> <td><math>\Delta C/C</math></td> <td><math>\leq \pm 1\%</math> or <math>\pm 1pF</math>, whichever is larger</td> <td><math>\leq \pm 15\%</math></td> </tr> </table> <p>No visible damage.</p>	Item	C0G	X7R	$\Delta C/C$	$\leq \pm 1\%$ or $\pm 1pF$ , whichever is larger	$\leq \pm 15\%$	<p>Preheating conditions: up-category temperature, 1h  Recovery time: 24±1h  Initial Measurement  Cycling Times: 5 times, 1 cycle, 4 steps:</p> <table border="1" data-bbox="893 716 1444 985"> <thead> <tr> <th>Step</th> <th>(Temperature)</th> <th>(Time)</th> </tr> </thead> <tbody> <tr> <td>1</td> <td>(Low- category temp.): C0G/X7R: -55℃</td> <td>30min</td> </tr> <tr> <td>2</td> <td>(Normal temp.): +20℃</td> <td>2~3min</td> </tr> <tr> <td>3</td> <td>(Up- category temp.): C0G/X7R: +125℃</td> <td>30min</td> </tr> <tr> <td>4</td> <td>(Normal temp.): +20℃</td> <td>2~3min</td> </tr> </tbody> </table> <p>Recovery time after test: 24±2h</p>	Step	(Temperature)	(Time)	1	(Low- category temp.): C0G/X7R: -55℃	30min	2	(Normal temp.): +20℃	2~3min	3	(Up- category temp.): C0G/X7R: +125℃	30min	4	(Normal temp.): +20℃	2~3min
Item	C0G	X7R																					
$\Delta C/C$	$\leq \pm 1\%$ or $\pm 1pF$ , whichever is larger	$\leq \pm 15\%$																					
Step	(Temperature)	(Time)																					
1	(Low- category temp.): C0G/X7R: -55℃	30min																					
2	(Normal temp.): +20℃	2~3min																					
3	(Up- category temp.): C0G/X7R: +125℃	30min																					
4	(Normal temp.): +20℃	2~3min																					
Humidity load	<table border="1" data-bbox="335 1120 957 1433"> <tr> <td rowspan="2"><math>\Delta C/C</math></td> <td>C0G</td> <td><math>\leq \pm 7.5\%</math> or <math>\pm 0.75pF</math>, whichever is larger.</td> </tr> <tr> <td>X7R</td> <td>-12.5% ~ +12.5%</td> </tr> <tr> <td>DF</td> <td colspan="2">Not more than twice of initial value.</td> </tr> <tr> <td rowspan="2">IR</td> <td>C0G</td> <td><math>R_i \geq 5000M\Omega</math> 或 <math>R_i \cdot C_R \geq 50S</math> whichever is smaller.</td> </tr> <tr> <td>X7R</td> <td><math>R_i \geq 1000M\Omega</math> 或 <math>R_i \cdot C_R \geq 10S</math> whichever is smaller.</td> </tr> <tr> <td colspan="3">Appearance: No visible damage.</td> </tr> </table>	$\Delta C/C$	C0G	$\leq \pm 7.5\%$ or $\pm 0.75pF$ , whichever is larger.	X7R	-12.5% ~ +12.5%	DF	Not more than twice of initial value.		IR	C0G	$R_i \geq 5000M\Omega$ 或 $R_i \cdot C_R \geq 50S$ whichever is smaller.	X7R	$R_i \geq 1000M\Omega$ 或 $R_i \cdot C_R \geq 10S$ whichever is smaller.	Appearance: No visible damage.			<p>※ Pretreatment (ClassII) :After preheating at 140℃~150℃ for 1h±10min, place at room temperature for 24±2h.  Temperature: 40±2℃ Humidity: 90~95%RH  Voltage: Rated Voltage Duration: 500h  Recovery conditions: Room temperature  Recovery Time: 24h±2h</p>					
$\Delta C/C$	C0G		$\leq \pm 7.5\%$ or $\pm 0.75pF$ , whichever is larger.																				
	X7R	-12.5% ~ +12.5%																					
DF	Not more than twice of initial value.																						
IR	C0G	$R_i \geq 5000M\Omega$ 或 $R_i \cdot C_R \geq 50S$ whichever is smaller.																					
	X7R	$R_i \geq 1000M\Omega$ 或 $R_i \cdot C_R \geq 10S$ whichever is smaller.																					
Appearance: No visible damage.																							
Damp heat, steady state	<table border="1" data-bbox="335 1534 957 1870"> <tr> <td rowspan="2"><math>\Delta C/C</math></td> <td>C0G</td> <td><math>\leq \pm 2\%</math> or <math>\pm 0.2pF</math>, whichever is larger.</td> </tr> <tr> <td>X7R</td> <td>-10% ~ +10%</td> </tr> <tr> <td>DF</td> <td colspan="2">Not more than twice of initial value.</td> </tr> <tr> <td rowspan="2">IR</td> <td>C0G</td> <td><math>R_i \geq 5000M\Omega</math> 或 <math>R_i \cdot C_R \geq 50S</math> whichever is smaller.</td> </tr> <tr> <td>X7R</td> <td><math>R_i \geq 1000M\Omega</math> 或 <math>R_i \cdot C_R \geq 10S</math> whichever is smaller.</td> </tr> <tr> <td colspan="3">Appearance: No visible damage.</td> </tr> </table>	$\Delta C/C$	C0G	$\leq \pm 2\%$ or $\pm 0.2pF$ , whichever is larger.	X7R	-10% ~ +10%	DF	Not more than twice of initial value.		IR	C0G	$R_i \geq 5000M\Omega$ 或 $R_i \cdot C_R \geq 50S$ whichever is smaller.	X7R	$R_i \geq 1000M\Omega$ 或 $R_i \cdot C_R \geq 10S$ whichever is smaller.	Appearance: No visible damage.			<p>Temperature: 40±2℃  Humidity: 90~95%RH  Duration: 500h  Recovery conditions: Room temperature  Recovery Time: 24h±2h</p>					
$\Delta C/C$	C0G		$\leq \pm 2\%$ or $\pm 0.2pF$ , whichever is larger.																				
	X7R	-10% ~ +10%																					
DF	Not more than twice of initial value.																						
IR	C0G	$R_i \geq 5000M\Omega$ 或 $R_i \cdot C_R \geq 50S$ whichever is smaller.																					
	X7R	$R_i \geq 1000M\Omega$ 或 $R_i \cdot C_R \geq 10S$ whichever is smaller.																					
Appearance: No visible damage.																							

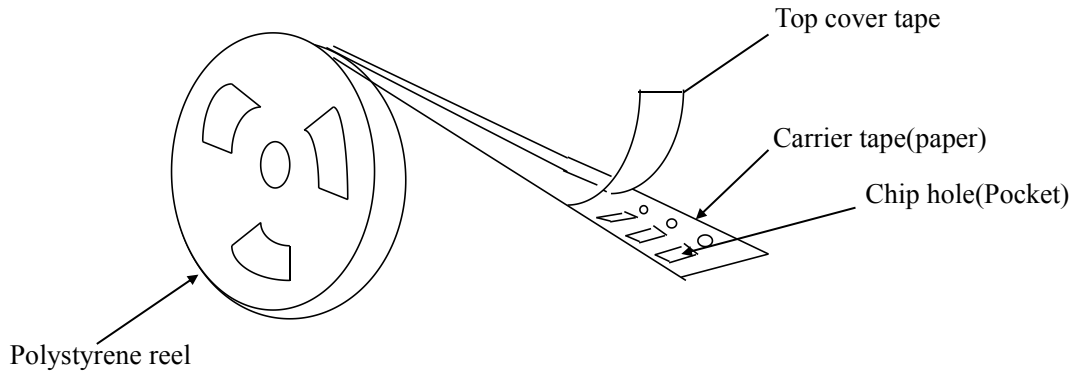
Item	Technical Specification	Test Method and Remarks																						
Passive Flammability	The tissue paper shall not ignite.	<p>The capacitor under test shall be held in the flame in the position which the tissue paper shall not ignite. best promotes burning.</p> <p>Each specimen shall only be exposed once to the flame.</p> <p>Time of exposure to flame : 30 s</p> 																						
Active Flammability	Cotton yarn will not burn	 <table border="1" data-bbox="587 1014 1008 1576"> <thead> <tr> <th>Code</th> <th>Parameter</th> </tr> </thead> <tbody> <tr> <td>C1,C2</td> <td>1uF±10%</td> </tr> <tr> <td>C3</td> <td>0.033uF±5% 10kV</td> </tr> <tr> <td>L1,L2, L3,L4</td> <td>1.5mH±20% 16A</td> </tr> <tr> <td>Ct</td> <td>3uF±5% 10Kv</td> </tr> <tr> <td>R</td> <td>100Ω±2%</td> </tr> <tr> <td>Cx</td> <td>(Sample capacitance)</td> </tr> <tr> <td>UAC</td> <td>UR±5%</td> </tr> <tr> <td>F</td> <td>(16A Fuse)</td> </tr> <tr> <td>UR</td> <td>(Rated voltage)</td> </tr> <tr> <td>Ut</td> <td>(Voltage Applied to Tantalum Capacitors for Energy Storage)</td> </tr> </tbody> </table> 	Code	Parameter	C1,C2	1uF±10%	C3	0.033uF±5% 10kV	L1,L2, L3,L4	1.5mH±20% 16A	Ct	3uF±5% 10Kv	R	100Ω±2%	Cx	(Sample capacitance)	UAC	UR±5%	F	(16A Fuse)	UR	(Rated voltage)	Ut	(Voltage Applied to Tantalum Capacitors for Energy Storage)
Code	Parameter																							
C1,C2	1uF±10%																							
C3	0.033uF±5% 10kV																							
L1,L2, L3,L4	1.5mH±20% 16A																							
Ct	3uF±5% 10Kv																							
R	100Ω±2%																							
Cx	(Sample capacitance)																							
UAC	UR±5%																							
F	(16A Fuse)																							
UR	(Rated voltage)																							
Ut	(Voltage Applied to Tantalum Capacitors for Energy Storage)																							



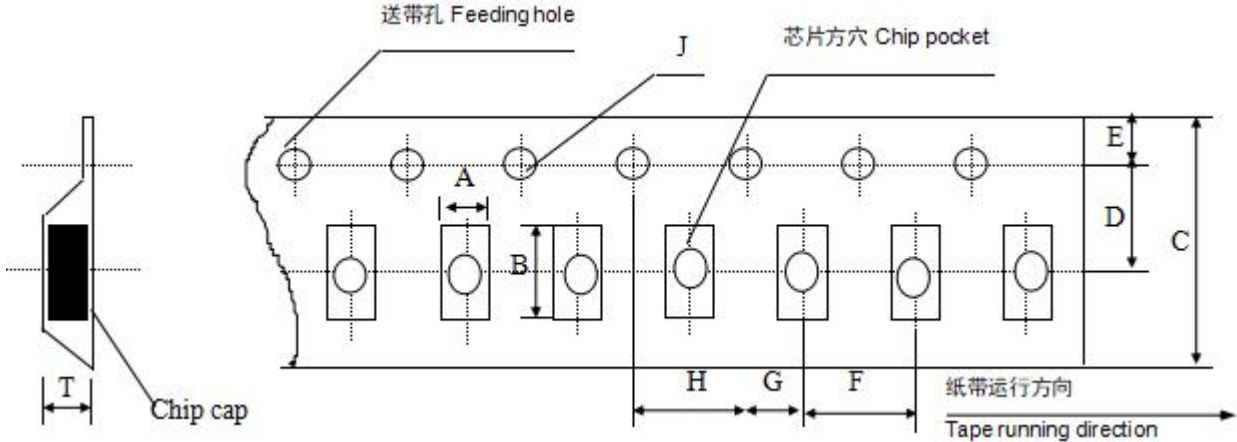
Item	Technical Specification			Test Method and Remarks												
Charge and discharge	$\Delta C/C$	C0G	$\leq \pm 2\%$ or $\pm 0.2\text{pF}$ , whichever is larger.	<p>As shown in the following figure, the device under test C is placed and subjected to 10000 charge and discharge cycles.</p>  <p>Charge voltage: <math>U_r</math>            Charge and discharge current: <math>\leq 1\text{A}</math></p> <table border="1" data-bbox="783 517 1428 779"> <thead> <tr> <th>Code</th> <th>Parameter</th> </tr> </thead> <tbody> <tr> <td>C</td> <td>Sample capacitance)</td> </tr> <tr> <td>R1</td> <td>Current-limiting resistor (discharge)</td> </tr> <tr> <td>R2</td> <td>Current-limiting resistor (charge)</td> </tr> <tr> <td>U</td> <td>Charge voltage</td> </tr> <tr> <td>S</td> <td>Switching device</td> </tr> </tbody> </table>	Code	Parameter	C	Sample capacitance)	R1	Current-limiting resistor (discharge)	R2	Current-limiting resistor (charge)	U	Charge voltage	S	Switching device
		Code	Parameter													
	C	Sample capacitance)														
	R1	Current-limiting resistor (discharge)														
	R2	Current-limiting resistor (charge)														
	U	Charge voltage														
S	Switching device															
X7R	-10% ~ +10%															
DF	Same to initial value.															
IR	C0G	$R_i \geq 2500\text{M}\Omega$ 或 $R_i \cdot C_R \geq 25\text{S}$ whichever is smaller.														
	X7R	$R_i \geq 1000\text{M}\Omega$ 或 $R_i \cdot C_R \geq 25\text{S}$ whichever is smaller.														
Appearance: No defects or abnormalities.																
Termination Adhesion	No visible damage.			Applied Force: 5N    Duration: $10 \pm 1\text{S}$												
Endurance	$\Delta C/C$	C0G	$\leq \pm 3\%$ 或 $\pm 0.3\text{pF}$ , whichever is larger.	<p>This test shall be conducted within one week after the completion of impulse voltage test.</p> <p>※ Pretreatment (ClassII) :After preheating at <math>140^\circ\text{C} \sim 150^\circ\text{C}</math> for <math>1\text{h} \pm 10\text{min}</math>, place at room temperature for <math>24 \pm 2\text{h}</math>.</p> <p>Temperature: <math>125^\circ\text{C}</math> (C0G X7R)    Duration: 1000h</p> <p>Charge/ Discharge Current: 50mA max.</p> <p>Applied Voltage: XA/XB: 1.25 Rated Voltage            YB: 1.7 Rated Voltage</p> <p>The capacitor is connected in series with a <math>47 \Omega \pm 5\%</math> resistor. Raise the voltage to 1000V once an hour for 0.1sec.</p> <p>Recovery Conditions: Room Temperature            Recovery Time: <math>24\text{h} \pm 2\text{h}</math></p>												
		X7R	-20% ~ +20%													
	DF	Not more than twice of initial value.														
	IR	C0G	$R_i \geq 4000\text{M}\Omega$ 或 $R_i \cdot C_R \geq 40\text{S}$ whichever is smaller.													
		X7R	$R_i \geq 2000\text{M}\Omega$ 或 $R_i \cdot C_R \geq 50\text{S}$ whichever is smaller.													
	Appearance: No visible damage.															

◆ **Package**

\* Embossed Taping



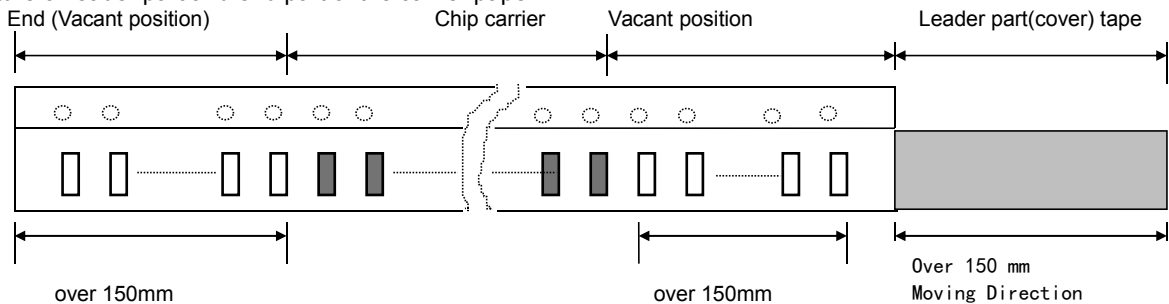
\* Dimensions of embossed taping for 0805~1812 type  
送带孔 Feeding hole 芯片方穴 Chip pocket



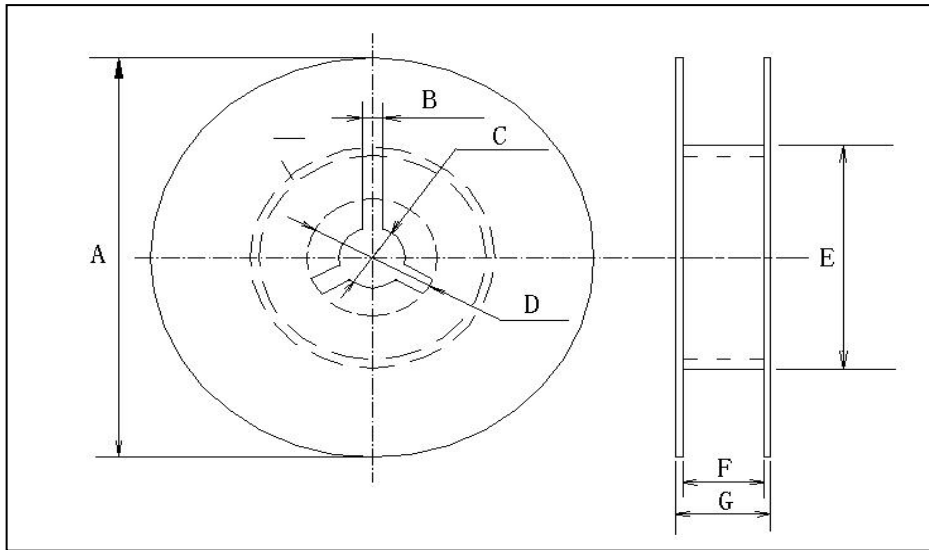
Code Tape size	A	B	C	D*	E	F	G*	H	J	T
SC08(1808)	2.20 ± 0.10	4.95 ± 0.10	12.00 ± 0.10	5.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10	2.00 ± 0.05	4.00 ± 0.10	1.50 -0/+0.10	3.0 Max
SC12(1812)	3.66 ± 0.10	4.95 ± 0.10	12.00 ± 0.10	5.50 ± 0.05	1.75 ± 0.10	8.00 ± 0.10	2.00 ± 0.05	4.00 ± 0.10	1.55 -0/+0.10	4.0 Max
SC11(2211) SC20(2220)	6.2 ±0.1	6.7 ±0.1	12.00 ± 0.10	5.50 ± 0.05	1.75 ± 0.10	8.00 ± 0.10	2.00 ± 0.05	4.00 ± 0.10	1.55 -0/+0.10	2.4 ± 0.10

Note: The place with "\*" means where needs exactly dimensions.

\* Structure of leader part and end part of the carrier paper



\* Reel Dimensions (unit: mm)

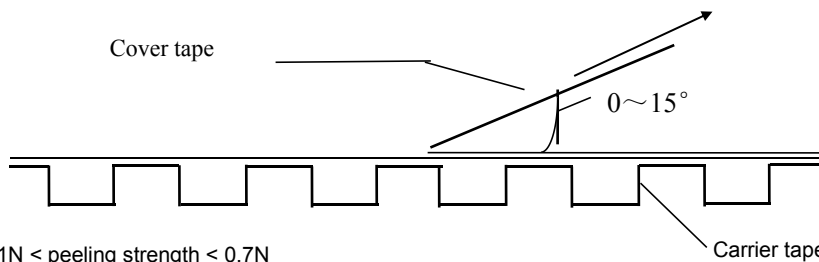


	A	B	C	D	E	F	G
7" REEL	$\phi 178 \pm 2.0$	3.0	$\phi 13 \pm 0.5$	$\phi 21 \pm 0.8$	$\phi 50$ 或更大 $\phi 50$ or more	$10.0 \pm 1.5$	12max

\* Taping specification: top tape peeling strength

Embossed Taping

Cover tape peeling direction



Standard:  $0.1N < \text{peeling strength} < 0.7N$

\* Bulk Case Package

unit:mm

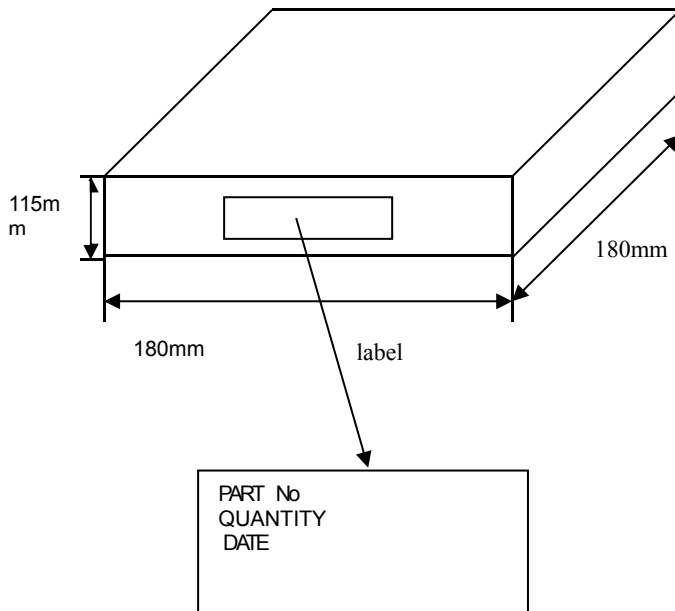
Symbol	A	B	T	C	D	E
Dimension	$6.80 \pm 0.10$	$8.80 \pm 1.00$	$12.00 \pm 0.10$	$15.00 + 0.10 / -0$	$2.00 + 0 / -0.10$	$4.70 \pm 0.10$
Symbol	F	W	G	H	L	I
Dimension	$31.50 + 0.20 / -0$	$36.00 + 0 / -0.20$	$19.00 \pm 0.35$	$7.00 \pm 0.35$	$110.00 \pm 0.70$	$5.00 \pm 0.35$

\* Packing Quantity

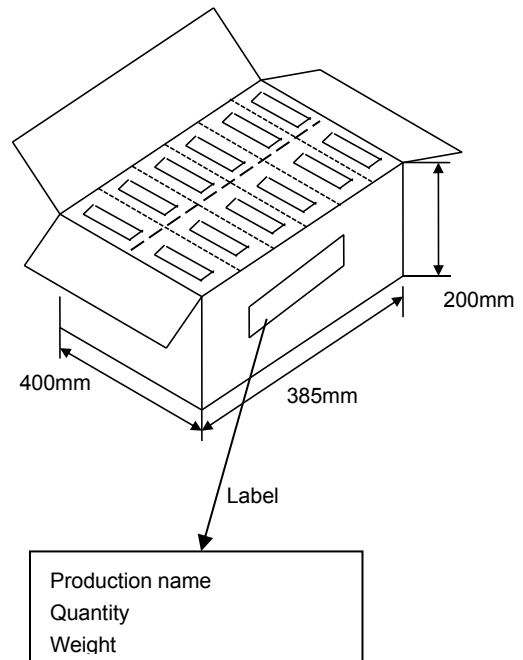
(SIZE)	Package Style & Quantity unit: pcs			
	(PT)	(ET)	(BC)	(BP)
SC08 (1808)	-----	2000	-----	2000
SC12 (1812)	-----	T $\leq$ 1.85mm 1000 T $>$ 1.85mm 500	-----	2000
SC11 (2211) SC20 (2220)	-----	500	-----	500

**\* Outer packing**

The first package  
 Quantity: 10 reels



The second package  
 Quantity: 6 cases


**◆ Storage Methods**

\* The guaranteed period for solderability is 12 months (Under deliver package condition).

\* Storage conditions:

Temperature 5~40℃

Relative Humidity 20~70%

**◆ Precautions For Use**

The Multi-layer Ceramic Capacitors (MLCC) may fail in a short circuit mode or in an open circuit mode when subjected to severe conditions of electrical environment and / or mechanical stress beyond the specified "rating" and specified "conditions" in the specification, which will result in burn out, flaming or glowing in the worst case. Following "precautions for safety" and Application Notes shall be taken in your major consideration. If you have a question about the precautions for handling, please contact our engineering section or factory.

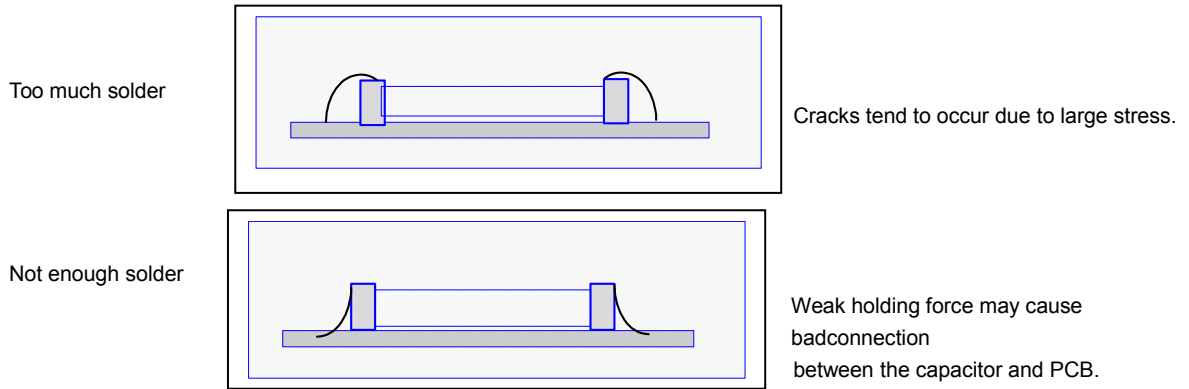
\* Soldering Profile

To avoid the crack problem by sudden temperature change, follow the temperature profile in the adjacent graph (refer to the graph in the enclosure page).

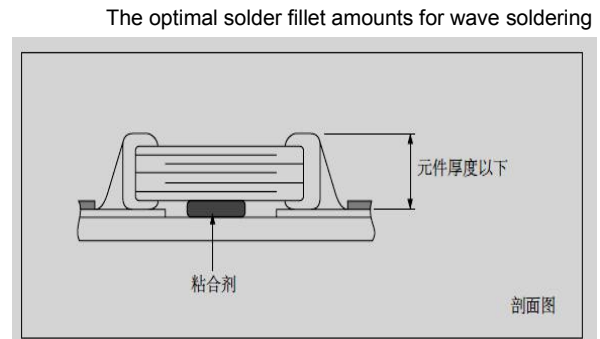
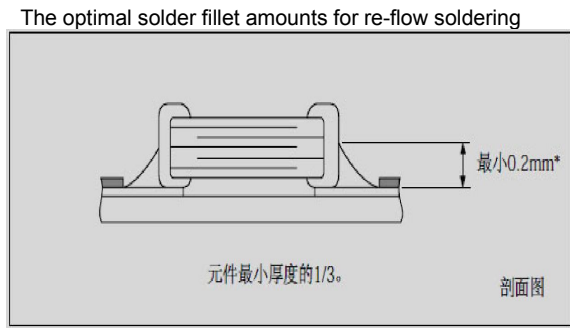
\* Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in capacitors. The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor. Therefore the soldering iron must be handled carefully, and pay much attention to the selection of the soldering iron tip and temperature contact of the tip.

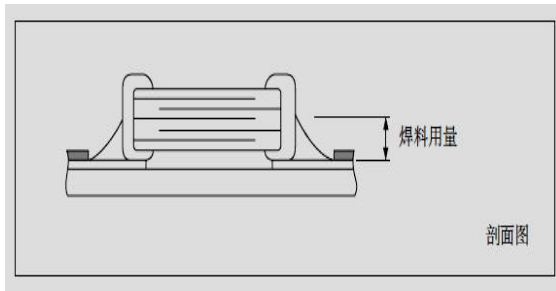
\* Optimum Solder Amount for Reflow Soldering



\* Recommended Soldering amounts



The optimal solder fillet amounts for reworking by using soldering iron



\* Recommended Soldering Method

Size	Temperature Characteristics	RatedVoltage	Capacitance	Soldering Method
SC08 (1808)	C0G/X7R	/	/	R
SC12 (1812)	C0G/X7R	/	/	R
SC11 (2211)	C0G/X7R	/	/	R
SC20 (2220)	C0G/X7R	/	/	R

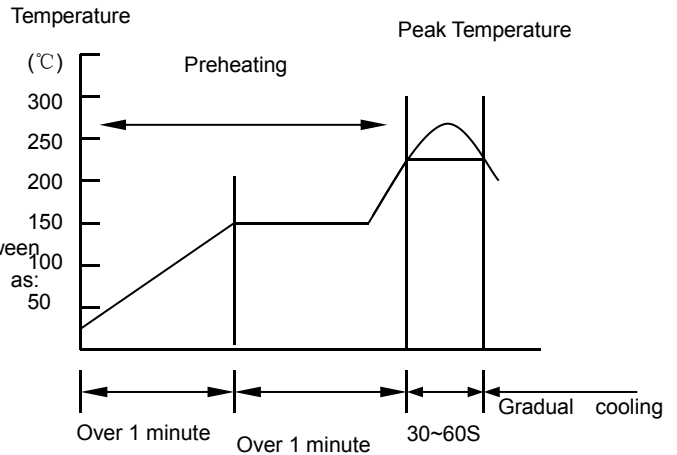
Soldering method: R—Reflow Solering  
W— Wave Soldering

### ◆ The temperature profile for soldering

\* (Re-flow soldering)

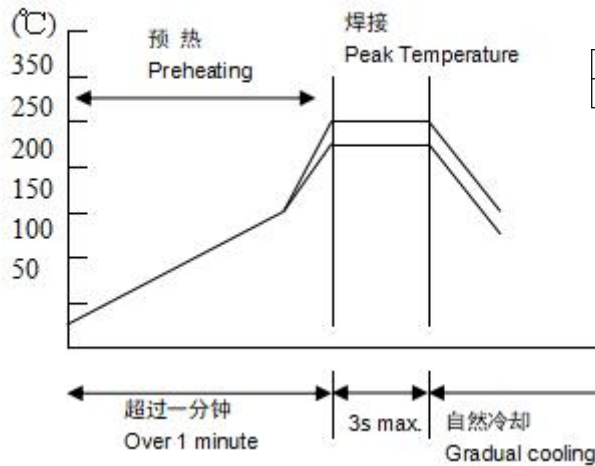
	Pb-Sn soldering	Lead-free soldering
Peak temperature	230°C~250°C	240°C~260°C

While in preheating, please keep the temperature difference between soldering temperature and surface temperature of chips as:  $T \leq 150^\circ\text{C}$ .



\* Wave soldering

温度 Temperature



	Pb-Sn soldering	Lead-free soldering
Peak temperature	230°C~260°C	240°C~270°C

While in preheating, please keep the temperature difference between soldering temperature and surface temperature of chips as:  $T \leq 150^\circ\text{C}$ .

\* Hand soldering

Item	Suggestions
Preheating	$\Delta \leq 130^\circ\text{C}$
Temperature of soldering iron head	Highest temperature: $350^\circ\text{C}$
Power of soldering iron	20W at the highest
Diameter of soldering iron head	1mm recommended
Soldering time	3s at the longest
Solder paste amount	$\leq 1/2$ chip thickness
Restricted conditions	Please avoid the direct contact between soldering iron head and ceramic components

\*The latest version of the content shall prevail

单击下面可查看定价，库存，交付和生命周期等信息

[>>FH\(风华高科\)](#)